

March 2013

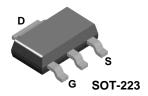
FQT13N06 N-Channel QFET® MOSFET 60 V, 2.8 A, 140 m Ω

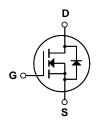
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 2.8 A, 60 V, $R_{DS(on)}$ =140 $m\Omega(Max.)$ @ V_{GS} =10 V, I_D =1.4 A
- Low Gate Charge (Typ. 5.8 nC)
- Low Crss (Typ. 15 pF)
- 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

G					
Symbol	Parameter		FQT13N06	Unit	
V _{DSS}	Drain-Source Voltage		60	V	
I _D	Drain Current - Continuous (T _C = 25°C)		2.8	А	
	- Continuous (T _C = 70°C)		2.24	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	11.2	А	
V _{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	85	mJ	
I _{AR}	Avalanche Current	(Note 1)	2.8	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	0.21	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns	
P _D	Power Dissipation (T _C = 25°C)		2.1	W	
	- Derate above 25°C		0.017	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes,		300	°C	
. L	1/8" from case for 5 seconds		300		

Thermal Characteristics

Symbol	Parameter	Тур	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		60	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	60			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -25 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 1.4 \text{ A}$		0.11	0.14	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_D = 1.4 \text{ A}$ (Note 4)		3.0		S
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		240 90	310 120	pF pF
	<u>'</u>	50				pF
C _{rss}	Reverse Transfer Capacitance			15	20	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 6.5 A,		5	20	ns
t _r	Turn-On Rise Time	$V_{DD} = 30 \text{ V}, I_D = 6.3 \text{ A},$ $R_G = 25 \Omega$		25	60	ns
t _{d(off)}	Turn-Off Delay Time	1 (G = 20 12		8	25	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		15	40	ns
Qg	Total Gate Charge	V _{DS} = 48 V, I _D = 13 A,		5.8	7.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		2.0		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		2.5		nC
	ource Diode Characteristics a	nd Maximum Ratings		2.5		n
I _S	Maximum Continuous Drain-Source Diode Forward Current				2.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F				11.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.8 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 13 \text{ A},$		39		ns
Q_{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		40		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 12.6mH, I_{AS} = 2.8A, V_{DD} = 25V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq 13A, di/dt \leq 300A/us, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

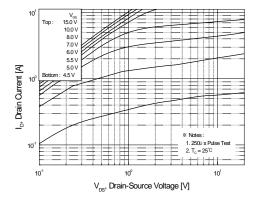


Figure 1. On-Region Characteristics

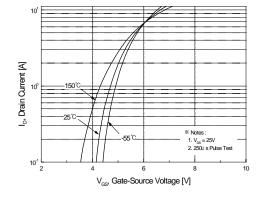


Figure 2. Transfer Characteristics

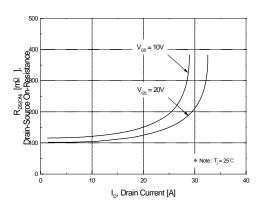


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

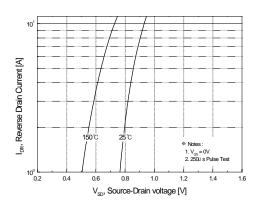


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

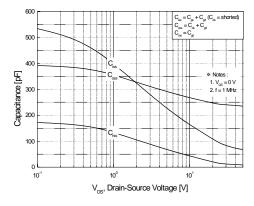


Figure 5. Capacitance Characteristics

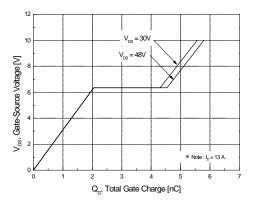
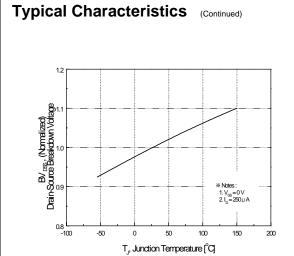


Figure 6. Gate Charge Characteristics



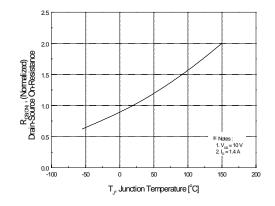
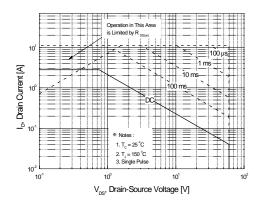


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



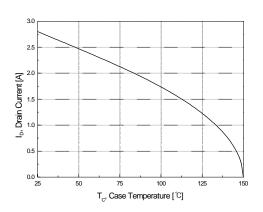


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

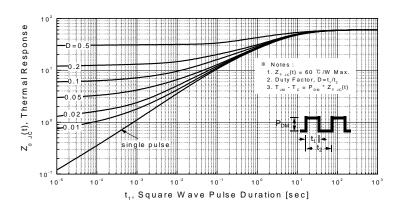
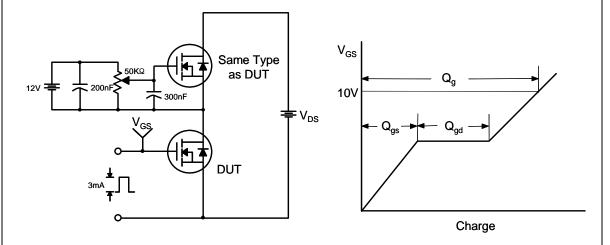
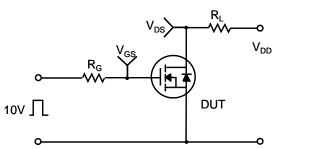


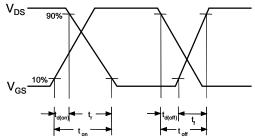
Figure 11. Transient Thermal Response Curve

Gate Charge Test Circuit & Waveform

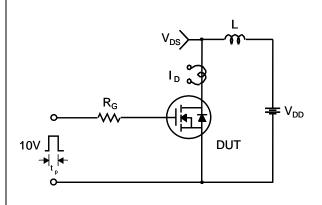


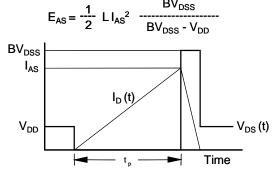
Resistive Switching Test Circuit & Waveforms

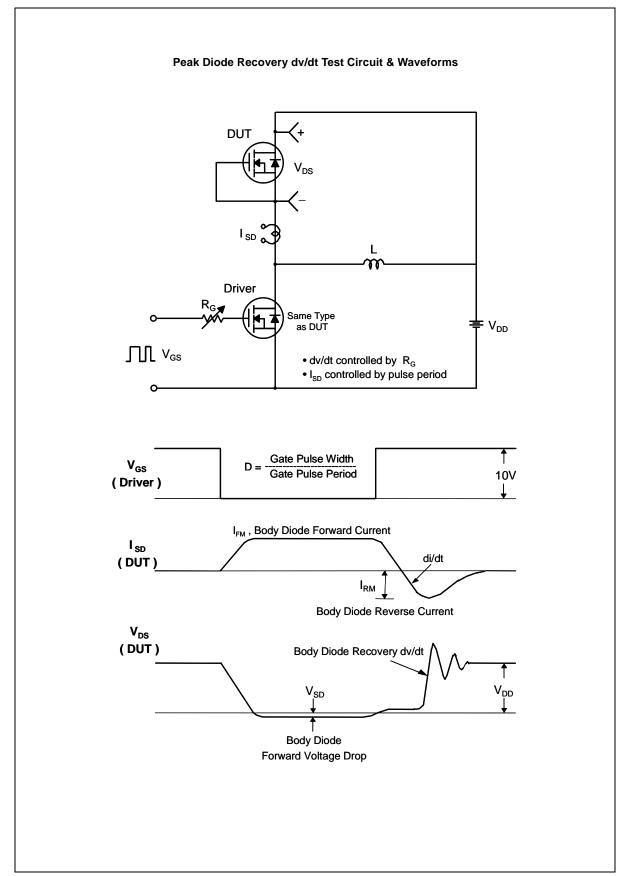


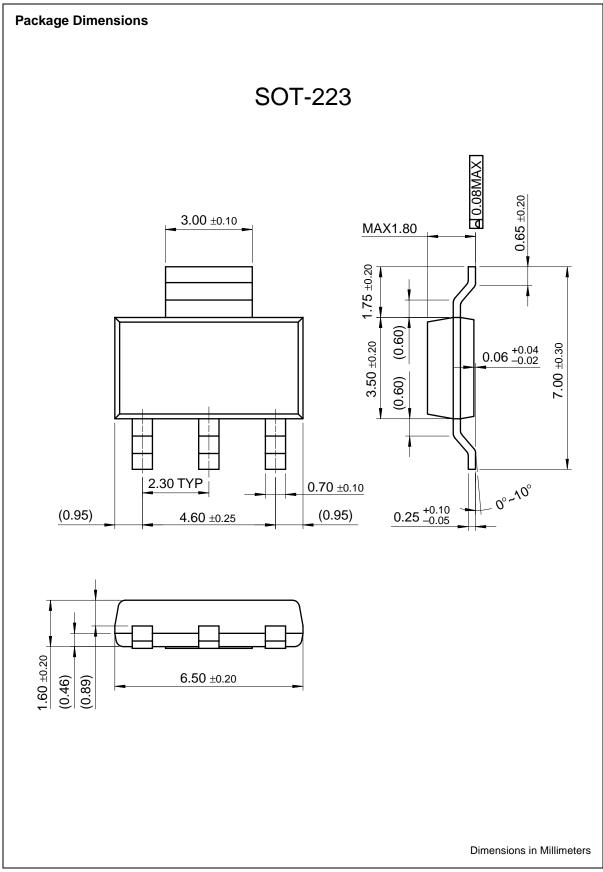


Unclamped Inductive Switching Test Circuit & Waveform













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